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Thermal profiling of solid-state active media

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Abstract

© 2018 IEEE. The fluorescence intensity ratio technique to the thermal profiling of solid-state laser materials is developed. The temperature distribution inside the excited area of LiY0.8Yb0.2F4: Tm3+(0.2 at.%) crystals during z-scanning was studied.

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Keywords

Solid-state active media, Thermal effects, Thermal sensor

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